DATE:

# APPROVAL SPECIFICATION

**ROHS** COMPLIANT

microgate

PRODUCT NAME: SMD power inductor

YOUR PART NO. :

OUR PART NO.: MPIH252010 Series

VERSION: V2.0

RECEPTION	2	Y	
THE SPECIFICAT	TION HAS BEEN ACCEP	TED.	
	XV		
•	DATE:		
COMPANY:			
CFMD	CHKD	RCVD	
XY			

MANUFACTURING NAME

SHENZHEN MICROGATE TECHNOLOGY CO. , LTDAddress: Microgate Smart Park, Technology Road, Zhukeng<br/>Community, Longtian Street, Pingshan District, Shenzhen.CFMD.Postcode: 518122TEL: 86-755-28085000CharlesFAX: 86-755-28085605CharlesCharles

CFMD.	CHKD.	DSGD.
Charles	Wang Yusheng	Liu Wei



# CATALOG

	Component SPEC Version Record	3
1	Scope	4
2	Product Identification	4
3	Appearance, Dimensions and Material	4
4	Testing Conditions	4
5	Electrical Characteristics And Test Instruments	5
6	Reliability	6-8
7	Recommended Soldering Conditions	8
8	Package Information	9
9	Visual inspection standard of product	10
10	Products Storage	10



# **Component SPEC Version Record**

Rev.	Effective Date	Changed Contents	Change Reasons	Approved By
1.0	Dec. 10.2012	New released	/	Charles
2.0	JUL. 31.2014	Change the Electrical Characteristics	The Electrical Characteristics improved	Charles



# 1. Scope

This specification applies to the MPIH252010 series of SMD power inductor.

# 2. Product Identification

<u>MPIH</u>	<u>252010</u> –	<u>1R5</u>	M	-	LF
1	2	3	(4)		5

<sup>①</sup> Product Symbol (H type SMD power inductor)

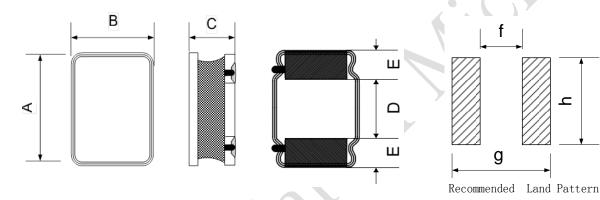
O Product dimensions (2.5×2.0×1.0mm)

- ③ Inductance Value: (R68:0.68 uH 1R5: 1.5uH 100: 10uH; 101: 100uH)
- ④ Inductance Tolerance:  $(M: \pm 20\%; N: \pm 30\%)$

⑤ Lead free product.

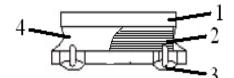
# 3. Appearance, Dimensions and Material

3.1 Appearance and dimensions



Dimensions in mm							
А	В	C	D	Е	f	g	h
2.50±0.20	2.00±0.20	1.00Max.	0.90±0.2	0.80±0.2	0.80 Тур.	2.50 Тур.	2.00 Тур.

# 3.2 Material List



No.	Item	Material
1	Core	Ni-Zn Ferrite
2	Wire	Enameled Copper Wire
3	Terminal Electrode	Ag/Ni/Sn/Cu
4	Magnetic Glue	Epoxy resin and magnetic powder

# 4. Testing Conditions

Unless otherwise specified, the standard conditions for measurement/test as: Ambient Temperature : 5 to 35 ℃ Relative Humidity: 25 to 85% RH Atmospheric Pressure: 86 to 106 kPa

If any doubt on the results, measurements/tests should be made within the following limits: Ambient Temperature :  $25\pm1\,^\circ C$ Relative Humidity: 60 to 70% RH Atmospheric Pressure: 86 to 106 kPa

### SHENZHEN MICROGATE TECHNOLOGY CO., LTD.

Add: Microgate Smart Park, Technology Road, Zhukeng Community, Longtian Street, Pingshan District, Shenzhen. Tel: +86-755-28085000 Fax: +86-755-28085605 Postcode: 518122

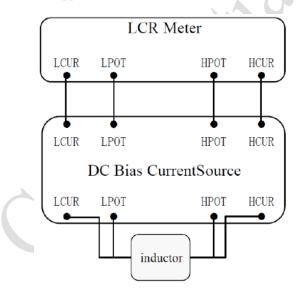


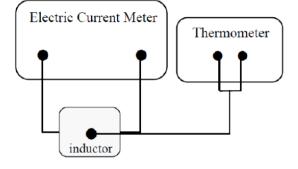
# **5. Electrical Characteristics And Test Instruments**

Microgate Part No.	Inductance L (uH)	DCF	R(Ω)	Isa (A	ut <sup>•1</sup> A)		ns <sup>•2</sup> A)
	1MHz/1V	Max.	Тур.	Max.	Тур.	Max.	Тур.
MPIH252010-R47M-LF	0.47±20%	0.042	0.035	3.40	3.60	3.20	3.50
MPIH252010-R68M-LF	0.68±20%	0.058	0.045	2.80	3.20	2.75	3.20
MPIH252010-1R0M-LF	1.0±20%	0.072	0.055	2.00	2.70	2.45	2.70
MPIH252010-1R5M-LF	1.5±20%	0.108	0.090	1.80	2.00	1.80	2.00
MPIH252010-2R2M-LF	2.2±20%	0.142	0.115	1.55	1.70	1.55	1.75
MPIH252010-3R3M-LF	3.3±20%	0.270	0.225	1.45	1.50	1.15	1.25
MPIH252010-4R7M-LF	4.7±20%	0.330	0.275	1.15	1.25	1.00	1.10
MPIH252010-100M-LF	10±20%	0.660	0.550	0.80	0.90	0.60	0.70

#### Test instruments and remarks

- \* All test data is referenced to  $25^{\circ}$ C ambient.
- \* L test by CHROMA 3302 meter or equivalent.
- \* DCR test by Tonghui TH2516B meter or equivalent.
- \* CHROMA 3302 and 1320 meter for IDC.
- \* Isat: DC current (A) that will cause L0 to drop approximately 30%.
- \* Irms: DC current (A) that will cause an temperature rise  $\triangle$  T approximate to 40°C.
- \* The rated current as listed is either the saturation current or the heating current depending on which value is lower.
- \* Operating temperature:  $-40^{\circ}$ C to  $+125^{\circ}$ C (Including self-heating)
- \* The part temperature (ambient + temp rise) should not exceed 125°C under worse case operating conditions. Circuit design, component placement, PCB trace size and thickness, airflow and other cooling provision all affect the part temperature. Part temperature should be verified in the end application.





Isat test schematic diagram

Irms test schematic diagram



# 6. Reliability

No.	Item	Requirements	Test Methods and Remarks	Reference	Sample Size
1	Solderability	<ul><li>(1) No physical damage.</li><li>(2) Terminal area must have 95% min. solder coverage.</li></ul>	<ul> <li>①Temperature:245±5°C, flux 5-10 s.</li> <li>②Sample immersion tin furnace 5 ±0.5s.</li> <li>③Immersed and in and out of speed: 25 ±6mm/s.</li> </ul>	AEC-Q200 (J-STD-002)	15
2	Resistance to Soldering Heat		<ul> <li>①The peak temperature: 260+5/-0°C.</li> <li>②Reflow:3times.</li> <li>③Temperature curve is as below:</li> <li>265℃</li> <li>Peak 265℃</li> <li>Max. Ramp Up Rate=3℃/s</li> <li>200℃</li> <li>217℃</li> <li>200℃</li> <li>60~180</li> <li>25℃</li> <li>60~180</li> <li>150℃</li> <li>50℃</li> <li>60~180</li> <li>50℃</li> <li>60~180</li> <li>50℃</li> <li>60~180</li> <li>50℃</li> <li>60~180</li> <li>50℃</li> <li>60~180</li> <li>50℃</li> <li>60~180</li> <li>60~</li></ul>	AEC-Q200 (MIL-STD-20 2 Method 210)	30
3	High Temperature Storage	(1) No physical	①Temperature: 125 ±2°C.         ②Time : 1000 hours.         ③Measurement at 24 ±4 hours after test conclusion.         Temperature         125°C         Room         24H         0         1000H	AEC-Q200 (MIL-STD -202 Method 108)	77
4	Low Temperature Storage	damage. (2)   ΔL0/L0   ≤10%	①Temperature: -55±2°C. ②Time : 1000 hours. ③Measurement at 24±4 hours after test conclusion. Room Temp. 0 -55°C Low temperature 24H Time Temp.	JESD22-A119	77
5	Thermal shock		<ul> <li>①First -40°C for 15 minutes, last 125°C 15minutes as 1 cycle. Go through 300 cycles.</li> <li>②Max transfer time is 20 second.</li> <li>③Measurement at 24±4 hours after test conclusion.</li> <li>125°C 15 min. 15 min.</li> <li>Ambient</li></ul>	MIL-STD -202 Method 107	30



No.	Item	Requirements	Test Methods and Remarks	Reference	Sample Size
6	Humidity Resistance		1000 hours, 85 °C/85% RH. 2 Unpowered. 3 Measurement at 24 ±4 hours after test conclusion. High temperature High humidity 85 °C Room Temp. 24H 0 1000H Time	AEC-Q200 (MIL-STD -202 Method 103)	77
7	Terminal Strength		<ul> <li>①The test samples shall be soldered to the board.</li> <li>②17.64N, 60s.</li> <li>Press tools Shear Force</li> </ul>	AEC-Q200 (AEC-Q200-0 06)	30
8	Board Flex	<ul> <li>(1) No physical damage.</li> <li>(2)   ΔL0/L0   ≤10%</li> </ul>	<ul> <li>1) Part mounted on a 100mm*40mm FR4 PCB board, which is 1.6±0.2 mm thick and as a Layer-thickness 35 μm ±10 μm.</li> <li>2) Bending speed is 1mm/s.</li> <li>3) Keeping the P.C Board 2 mm minimum for 60 seconds.</li> </ul> Support Solder Chip Printed circuit board before testing 45±2 Printed circuit board under test Unit: mm	AEC-Q200 (AEC-Q200-0 05)	30
9	Drop		<ul><li>①Height: 1 m, Free fall, 10times.</li><li>②Direction: 1 Angle, 1side, 2surface.</li></ul>	JESD22-B111	30
10	Vibration		<ol> <li>1) Frequency range : 10~2000Hz.</li> <li>(2) Amplitude: 1.5mm, 5g.</li> <li>(3) Sweep time and duration: 10~2000~10Hz for 20 minutes.</li> <li>(4) Each four hours(12 times) in X,Y,Z direction, 12 hours in total.</li> </ol>	AEC-Q200 (MIL-STD-20 2 Method 204)	30

SHENZHEN MICROGATE TECHNOLOGY CO., LTD.



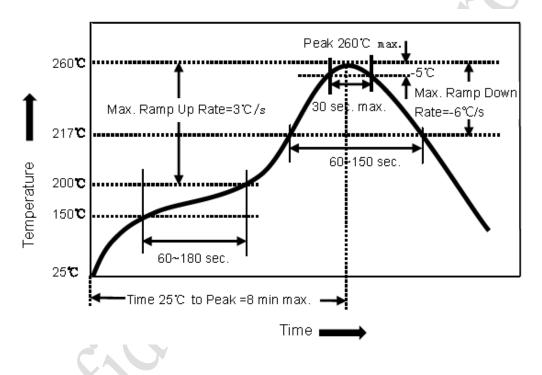
No.	Item	Requirements	Test Methods and Remarks	Reference	Sample Size
11	Loading at High Temperature	<ul> <li>(1) No physical damage.</li> <li>(2)   ΔL0/L0   ≤10%</li> </ul>	<ol> <li>①Temperature: 85±2°C.</li> <li>②Time : 1000 hours.</li> <li>③Applied Current : Rated current.</li> <li>④Measurement at 24±4 hours after test conclusion.</li> </ol>	AEC-Q200 (MIL-PRF-27)	77

\*All above experiments items need 3 Lot., sample size is as specified in the table above.

\*Sample size standard is from AEC-Q200 : qualification sample size requirements.

# 7. Recommended Soldering Conditions

(1) Reflow soldering conditions



\*Above reflow soldering curve is from J-STD-020D.

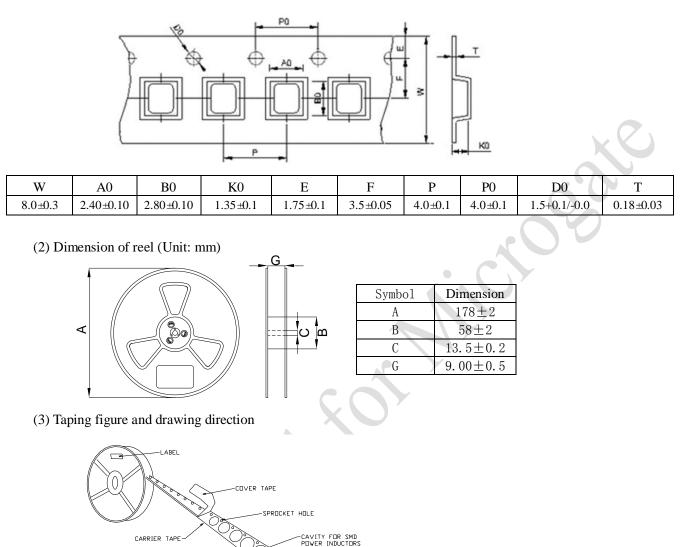
# (2) Iron soldering

The following conditions must be strictly followed when using a soldering iron.

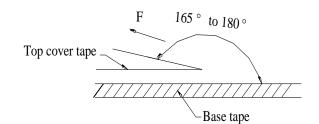
Pre-heating	150°C 1 minute
Tip temperature	350°C max
Soldering iron output	30w max
End of soldering iron	φ1mm max
Soldering time	3 seconds max

# 8. Package Information

(1) Dimension of tape (Unit: mm)



- (4) Packaging quantities: 2000PCS/Reel.
- (5) Peeling strength of cover tape:
  - The peel force of top cover tape shall be between 0.10N to 1.0N \*the peel force standard is from EIA-481-D



Room Temp.	Room Humidity	Room aim	Peel Speed
(°C)	(%)	(hpa)	mm/min
5-35	45-85	860-1060	300

# SHENZHEN MICROGATE TECHNOLOGY CO., LTD.

Add: Microgate Smart Park, Technology Road, Zhukeng Community, Longtian Street, Pingshan District, Shenzhen.Tel: +86-755-28085000Fax: +86-755-28085605Postcode: 518122



No.	Defect Item	Graphic	<b>Rejection identification</b>	Acceptance
1	Core defect		l >L/6 or w >W/6, NG.	AQL=0.65
2	Missing resin		The area of missing resin more than single face, NG	AQL=0.65
3	Cold solder		L more than 1 mm, NG.	AQL=0.65
4	Solder uneven		H>0.1mm. NG.	AQL=0.65

# 9. Visual inspection standard of product

# **10. Products Storage**

(1) Storage period

Products which inspected in MICROGATE over 12 months ago should be examined and used, which can be confirmed with inspection No. marked on the container. Solderability should be checked if this period is exceeded.

(2) Storage conditions

Products should be storage in the warehouse on the following conditions:

Temperature: -10 ~+ 35°C

Humidity: Less than 70% relative and humidity

No rapid change on temperature and humidity.

- (3) Don't keep products in corrosive gases such as sulfur, chlorine gas or acid, or it may cause oxidization of electrode, resulting in poor solderability.
- (4) Products should be storage on the palette for the prevention of the influence from humidity, dust and so on.
- (5) Products should be storage in the warehouse without heat shock, vibration, direct sunlight and so on.
- (6) Products should be storage under the airtight packaged condition.

#### SHENZHEN MICROGATE TECHNOLOGY CO., LTD.